

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	107	RET and manufacturability	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/05/01 10:20
L2	2460	RET and (manufacturab\$5 or applicab\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/05/01 10:34
L3	23	ORC and 2	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/05/01 10:35
L4	3	percentage and 3	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/05/01 10:36
L5	13	ratio and 3	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/05/01 10:19
L6	2	((manufacturab\$5 or applicab\$5) with ratio) and 3	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/05/01 10:52
L7	3	((manufacturab\$5 or applicab\$5) same ratio) and 3	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/05/01 10:31
L8	243	RET and (manufacturab\$5 or printab\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/05/01 10:49
L9	19	ORC and 8	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/05/01 10:36
L10	167	rule and 8	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/05/01 10:36
L11	40	percentage and 10	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/05/01 10:37

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L12	2	ORC and 11	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/05/01 10:37
L13	98	(percentage or ratio) and 10	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/05/01 10:37
L14	11	ORC and 13	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/05/01 10:37
L15	1	(RET and (manufacturab\$5 or printab\$5 or applicab\$5)).clm.	US-PGPUB	OR	ON	2007/05/01 11:02
L16	10	((resolution with enhancement) and (manufacturab\$5 or printab\$5 or applicab\$5)).clm.	US-PGPUB	OR	ON	2007/05/01 10:51
L17	1	(percentage or ratio).clm. and 16	US-PGPUB	OR	ON	2007/05/01 10:51
L18	2747	716/4.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/05/01 11:10
L19	1	("20070031745").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2007/05/01 11:02
L20	2095	716/5.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/05/01 11:44
L21	1691	716/6.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/05/01 12:00
L22	1455	716/19.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/05/01 12:14
L23	360	716/20.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/05/01 12:40
L24	8776	430/5.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2007/05/01 12:40

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